

Notice of References Cited	Application/Control No. 10/577,421	Applicant(s)/Patent Under Reexamination SAINTY ET AL.	
	Examiner Michael Maskell	Art Unit 2881	Page 1 of 1

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*	E	US-6,849,854 B2	02-2005	Sainty, Wayne Gregory	250/423R
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	M	US-			

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NON-PATENT DOCUMENTS

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	U	Pollard, et al. "Electron-impact ionization time-of-flight mass spectrometer for molecular beams" Rev. Sci. Instrum. 56(1) January 1987 pp. 32-37
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.